

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexam	
	09/750,317	Robert Schreiber	
	Examiner JACQUES VEILLARD	Art Unit 2175	Page 1 of 1

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B	6,434,745	8/2002	Conley, Jr. et al.	717	177
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**NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
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V	Michael V. Mannino et al.: Statistical Profile Estimation in Database System, ACM, Vol.20, No.3, Sept. 88, pp. 191-221
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X	Francesco M. Malvestuto: A Universal scheme Approach to Statistical Database Containing Homogeneous Summary Tables, ACM, Vol.18, No.4, Dec. 93, pp. 678-708.

<sup>1</sup>A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).

<sup>1</sup>Dates in MM-YYYY format are publication dates.

<sup>2</sup>Classifications may be U.S. or foreign.